

IRFP440B

500V N-Channel MOSFET

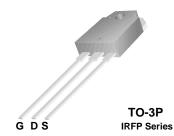
General Description

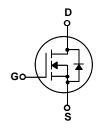
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies, power factor correction and electronic lamp ballasts based on half bridge.

Features

- 8.5A, 500V, $R_{DS(on)} = 0.8\Omega$ @V_{GS} = 10 V Low gate charge (typical 41 nC)
- Low Crss (typical 35 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		IRFP440B	Units
V _{DSS}	Drain-Source Voltage		500	V
I _D	Drain Current - Continuous (T _C = 25	°C)	8.5	Α
	- Continuous (T _C = 100°C)		5.4	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	34	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	320	mJ
I _{AR}	Avalanche Current	(Note 1)	8.5	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	16.2	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P_D	Power Dissipation (T _C = 25°C)		162	W
	- Derate above 25°C		1.3	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.77	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	5	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	I to 25°C	1	0.55		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 500 V, V _{GS} = 0 V				10	μΑ
		V _{DS} = 400 V, T _C = 125°C		-		100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$		ŀ		-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 4.25 A			0.65	0.8	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 4.25 A	(Note 4)		7.7		S
	ic Characteristics						
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V, } V_{GS} = 0 \text{ V,}$ f = 1.0 MHz			1400	1800	pF
Coss	Output Capacitance				145	190	pF
C _{rss}	Reverse Transfer Capacitance				35	45	pF
Switchi	ing Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DD} = 250 V, I _D = 8.0 A,		1	22	55	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$			65	140	ns
t _{d(off)}	Turn-Off Delay Time	1.6 20 22		-	125	260	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		75	160	ns
Qg	Total Gate Charge	$V_{DS} = 400 \text{ V}, I_{D} = 8.0 \text{ A},$		1	41	53	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		1	6.5	-	nC
Q _{gd}	Gate-Drain Charge		(Note 4, 5)		17	-	nC
Drain-S	Source Diode Characteristics a	nd Maximum Rating	s				
I _S	Maximum Continuous Drain-Source Diode Forward Current					8.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	e Forward Current				34	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 8.5 \text{ A}$		1		1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 8.0 \text{ A},$		1	390		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)			4.2		μС

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 8.0mH, I_{AS} = 8.5A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} ≤ 8.0A, di/dt ≤ 300A/µs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

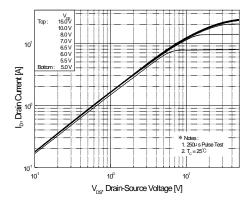


Figure 1. On-Region Characteristics

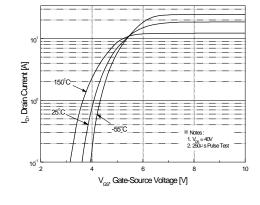


Figure 2. Transfer Characteristics

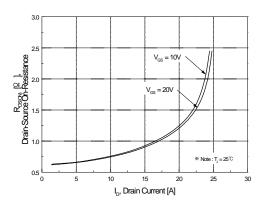


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

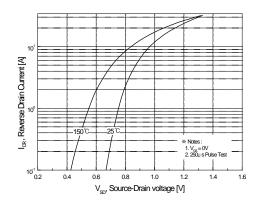


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

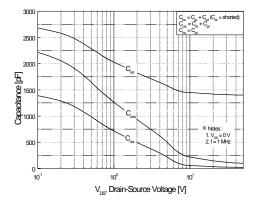


Figure 5. Capacitance Characteristics

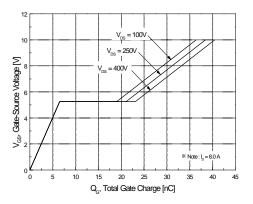


Figure 6. Gate Charge Characteristics

Rev. B, November 2001

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Typical Characteristics (Continued)

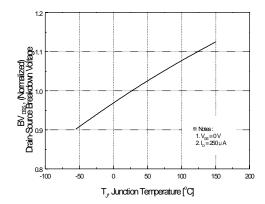
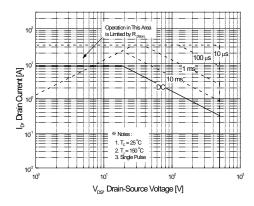


Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



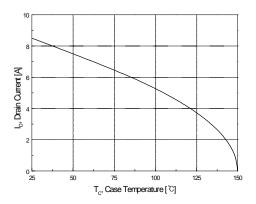


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

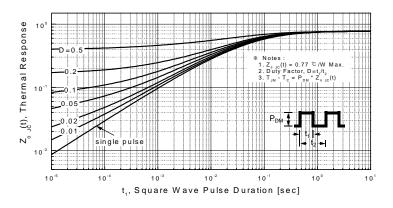
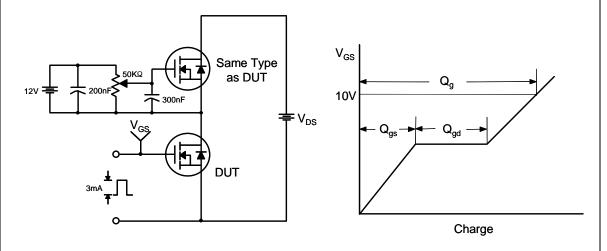
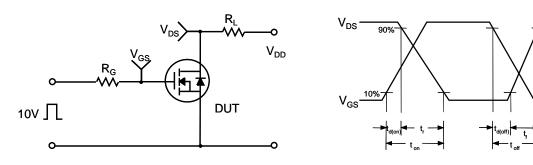


Figure 11. Transient Thermal Response Curve

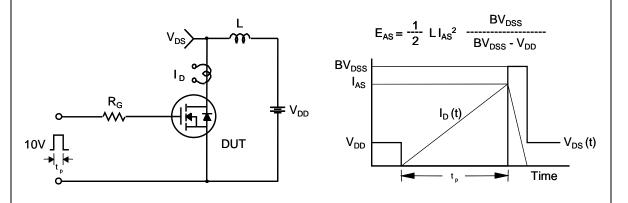
Gate Charge Test Circuit & Waveform



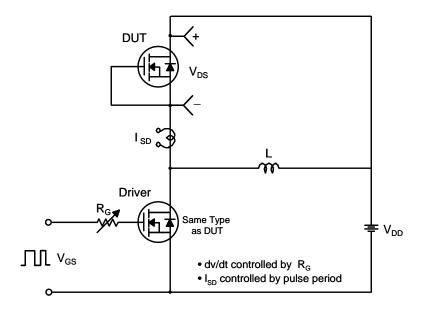
Resistive Switching Test Circuit & Waveforms

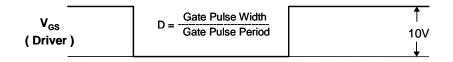


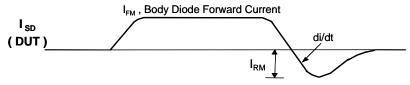
Unclamped Inductive Switching Test Circuit & Waveforms



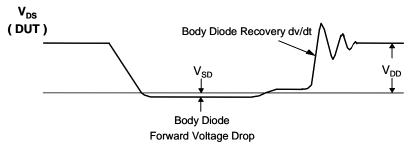
Peak Diode Recovery dv/dt Test Circuit & Waveforms

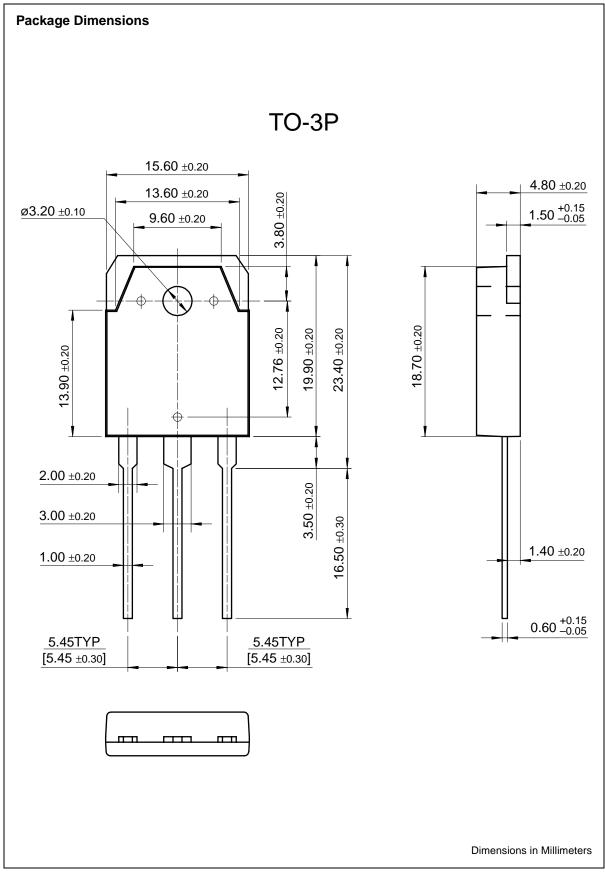






Body Diode Reverse Current





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